



ANALYSIS OF THE MEDIUM FIELD Q-SLOPE IN SUPERCONDUCTING CAVITIES MADE OF BULK NIOBIUM*

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Abstract

The quality factor of superconducting radio-frequency cavities made of high purity niobium is observed to decrease for increasing rf field in the medium field range (peak surface magnetic field between 20 and 80 mT). The causes for this effect are not clear yet. The dependence of the surface resistance from the peak surface magnetic field is often observed to be linear and quadratic. This paper will present an analysis of the medium field Q-slope data measured on cavities treated with buffered chemical polishing (BCP) at Jefferson Lab, as function of different treatments such as post-purification and low temperature baking. The data have been compared with a model involving a combination of the thermal feedback effect and of hysteresis losses due to "strong-links" formed on the niobium surface during oxidation.

Models for the medium field Q-slope

- Heating of the rf surface due to the niobium helium thermal resistance (global heating) [1]

$$R_s(T, B_p) = R_{sc}(T) \left[1 + \gamma' (T) \left(\frac{B_p}{B_c} \right)^2 \right] + O(B_p^4) \quad \text{Quadratic dependence}$$

$R_{sc}(T) = R_{BCS}(T) + R_{res}$ is the surface resistance at 15 mT

$B_c(0K) = 200$ mT is the critical field of niobium

$$\gamma' (T) = \frac{\partial R_s}{\partial T} \frac{B_c^2}{2} \left(\frac{d}{\kappa + R_s} \right) = R_{res}(T) \frac{B_c^2}{2kT^2} \left(\frac{d}{\kappa + R_s} \right)$$

- Global heating including an intrinsic nonlinear dependence of the BCS surface resistance due to pairbreaking effect [2]

$$R_s(T, B_p) = R_{sc}(T) \left[1 + \gamma (T) \left(\frac{B_p}{B_c} \right)^2 \right] \quad \text{Quadratic dependence}$$

$$\gamma (T) = \frac{R_{res}(T)}{R_{sc}(T)} \left(\frac{\Delta}{kT} \right)^2 + \gamma' (T)$$

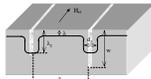
$C = 0.028$ at 1.5 GHz, depends on material parameters. C is weakly dependent on frequency

- Hysteresis losses due to Josephson fluxons penetrating in the niobium, particularly at grain boundaries, above about $B_{c1} \approx 30$ mT [3]

$$R_{sc}(B_p) = \frac{4}{3\pi} \frac{\omega}{J_c} \left[1 + (a/B_p)^2 \right]^{1/2} \frac{\lambda}{a} \frac{B_p}{B_c} \left(\frac{B_p}{B_c} \right) - R_c \left(\frac{B_p}{B_c} \right) \quad \text{Linear dependence}$$

$\omega_0 (\approx 5$ GHz) is a characteristic creation frequency. $J_c \approx 10^{11}$ A/m² is the Josephson critical current density. R_{res} is predicted to be temperature independent for $T < T_c/2$

Schematic representation of "strong-links" in niobium

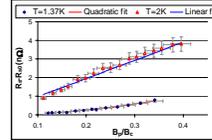


- $\lambda_J = 0.18$ μ m, Josephson penetration depth
- $a_J = 10-100$ μ m, "island" size
- $w = 0.001-0.1$ μ m, depth of oxide "cracks"
- $d_J = 2\lambda + \text{oxide thickness} = 0.082$ μ m

- [1] J. Halbritter, Proc. of the 38th Eloisatron Workshop, Erice, Italy (1999), p. 9.
- [2] A. Gurevich, Proc of the Pushing the Limits of SRF Workshop, Argonne, USA (2004) p. 17
- [3] J. Halbritter, J. Appl. Phys 97, 083904 (2005).

Data analysis

The plot of the experimental data of the surface resistance as function of B_p in the medium field range often shows a linear or quadratic dependence.



Average correlation factors (from 7 rf tests) for the linear and quadratic models at three different temperatures

Model	Avg. r^2 (2.2 K)	Avg. r^2 (2 K)	Avg. r^2 (1.37 K)
Quadratic	0.958	0.900	0.973
Linear	0.931	0.966	0.964

Data have been fitted including both linear and quadratic term

$$R_s(T, B_p) = R_{sc}(T) + R_{res}^l \left(\frac{B_p}{B_c} \right) + R_{res}^q \gamma' (T) \left(\frac{B_p}{B_c} \right)^2$$

The fit parameters are R_{sc} and the slopes γ^* and R_{res}^l , with the constraint that the values have to be positive

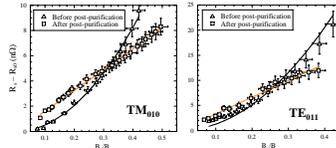
TM₀₁₀/TE₀₁₁ CEBAF single cell

Average values of the fit parameters at 2K before and after baking for the TM₀₁₀ mode (1.47 GHz) and TE₀₁₁ mode (2.82 GHz)



	Before post-purification		After 100-120 °C baking	
	TM ₀₁₀	TE ₀₁₁	TM ₀₁₀	TE ₀₁₁
R_{sc} (m Ω)	26.9 ± 0.2	9.1 ± 0.4	18.7 ± 0.2	36.3 ± 0.2
R_{res}^l (m Ω)	7.46 ± 1.46	0.003 ± 3.7	27.1 ± 1.3	5.32 ± 2.40
γ^*	1.55 ± 0.11	2.76 ± 0.14	0.97 ± 0.13	3.34 ± 0.14
r^2	0.985	0.984	0.988	0.987

	Before baking		After 100-120 °C baking	
	TM ₀₁₀	TE ₀₁₁	TM ₀₁₀	TE ₀₁₁
R_{sc} (m Ω)	28.7 ± 0.1	79.3 ± 0.3	23.3 ± 0.3	52.7 ± 0.3
R_{res}^l (m Ω)	16.4 ± 1.1	24.1 ± 2.8	34.1 ± 2.0	719 ± 1.5
γ^*	0.01 ± 0.07	0.00 ± 0.06	0.00 ± 0.13	0.25 ± 0.03
r^2	0.987	0.988	0.993	0.989



Theoretical estimates:

	Before post-purification	After post-purification
R_{sc}^{-1} (m Ω)	198	284
γ^*	0.67	1.47
R_{res}^l	2.33	3.80

Post-purified CEBAF single cell 1.47 GHz

Average values of the fit parameters before and after baking for 48h between 70°C and 180 °C

		T = 2 K	
	Before baking	After baking	
R_{sc} (m Ω)	21.6 ± 0.1	15.2 ± 0.2	
R_{res}^l (m Ω)	11.6 ± 1.1	20.2 ± 1.9	
γ^*	0.04 ± 0.10	0.10 ± 0.24	
r^2	0.952	0.950	

		T = 1.37 K	
	Before baking	After baking	
R_{sc} (m Ω)	4.81 ± 0.03	4.82 ± 0.06	
R_{res}^l (m Ω)	2.27 ± 0.31	4.39 ± 0.47	
γ^*	1.36 ± 0.14	1.46 ± 0.17	
r^2	0.982	0.988	

Theoretical estimates:

Temperature	R_{sc} (m Ω)	R_{res}^l (m Ω /K ²)	κ (W/m ² K)	γ^* (K)	γ
2 K	14	$1.06 \cdot 10^{-4}$	30	0.16	1.63
1.37 K	0.4	$4.67 \cdot 10^{-7}$	8	0.04	0.26

$R_{res}^l \approx 20$ m Ω (T-independent)

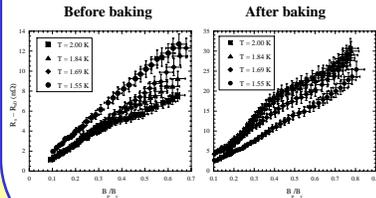
2.2 GHz Single crystal CEBAF HG single cell

Average values of the fit parameters before and after baking at 120°C for 48 h at different temperatures

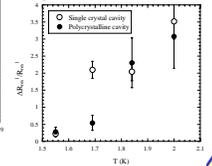


Post-purified single crystal cavity, before bake				
T (K)	R_{sc} (m Ω)	R_{res}^l (m Ω)	γ^*	r^2
2	29.1 ± 0.2	12.3 ± 1.3	0.00 ± 0.06	0.983
1.84	18.3 ± 0.2	14.3 ± 1.1	0.00 ± 0.08	0.994
1.69	8.7 ± 0.2	11.8 ± 1.0	0.95 ± 0.14	0.997
1.55	4.2 ± 0.1	20.0 ± 0.6	0.00 ± 0.2	0.999

Post-purified single crystal cavity, after bake				
T (K)	R_{sc} (m Ω)	R_{res}^l (m Ω)	γ^*	r^2
2	24.3 ± 1.1	55.4 ± 2.1	1.03 ± 0.05	0.980
1.84	15.0 ± 1.0	43.5 ± 1.5	1.77 ± 0.13	0.978
1.69	11.8 ± 0.2	36.7 ± 0.6	2.52 ± 0.08	0.995
1.55	10.1 ± 0.2	24.5 ± 0.8	2.81 ± 0.07	0.975



Change of the linear slope coefficient before and after baking for the single crystal cavity and a polycrystalline cavity of the same shape



Summary

- The medium field Q-slope data are well described by the sum of a linear and quadratic dependence of R_s vs B_p
- The quadratic slope coefficient γ^* is related to overheating of the cavity rf surface
 - The addition of a term due to BCS pairbreaking effect overestimates the values obtained from the data fit: $C(\Delta/kT)^2 < 0.06$ for niobium^{*}.
 - γ^* is reduced by post-purification due to the higher thermal conductivity and Kapitza conductance
 - The quadratic term dominates at frequencies > 2.2 GHz due to higher R_{BCS}
- The linear slope coefficient R_{res}^l could be explained by hysteresis losses
 - R_{res}^l is enhanced by baking, possibly due to a reduction of J_c
 - R_{res}^l seems to increase at higher frequencies, as predicted by the model
 - Under the assumption that the "island" size a_J is of the order of the grain size, an estimate of R_{res}^l gives good agreement with the fit result for post-purified cavities, but not for the "fine" grain and single crystal cavities
 - The linear slope seems to be smaller at lower temperatures, in the range 1.4-2K, but this dependence seems to be reversed by baking. The model predicts T-independent hysteresis losses.

*See Ref. [1].

